- Timing From Microseconds to Hours
- Astable or Monostable Operation
- Adjustable Duty Cycle
- TTL-Compatible Output Can Sink or Source up to 200 mA
- Designed To Be Interchangeable With Signetics NE555, SA555, SE555, and SE555C


## SE555C FROM TI IS NOT RECOMMENDED FOR NEW DESIGNS

## description

These devices are precision monolithic timing circuits capable of producing accurate time delays or oscillation. In the time-delay or monostable mode of operation, the timed interval is controlled by a single external resistor and capacitor network. In the astable mode of operation, the frequency and duty cycle can be controlled independently with two external resistors and a single external capacitor.
The threshold and trigger levels normally are two-thirds and one-third, respectively, of $\mathrm{V}_{\mathrm{CC}}$. These levels can be altered by use of the control-voltage terminal. When the trigger input falls below the trigger level, the flip-flop is set and the output goes high. If the trigger input is above the trigger level and the threshold input is above the threshold level, the flip-flop is reset and the output is low. RESET can override all other inputs and can be used to initiate a new timing cycle. When RESET goes low, the flip-flop is reset and the output goes low. When the output is low, a low-impedance path is provided between DISCH and ground.

The output circuit is capable of sinking or sourcing current up to 200 mA . Operation is specified for supplies of 5 V to 15 V . With a $5-\mathrm{V}$ supply, output levels are compatible with TTL inputs.
The NE555 is characterized for operation from $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$. The SA555 is characterized for operation from $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$. The SE555 and SE555C are characterized for operation over the full military range of $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$.

AVAILABLE OPTIONS

| $\mathrm{T}_{\text {A }}$ | PACKAGE |  |  |  |  | CHIP FORM <br> (Y) |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | $\mathrm{V}_{\text {THRES }}$ MAX $\mathrm{V}_{\mathrm{CC}}=15 \mathrm{~V}$ | SMALL OUTLINE <br> (D) | $\begin{aligned} & \text { CHIP CARRIER } \\ & \text { (FK) } \end{aligned}$ | CERAMIC DIP (JG) | PLASTIC DIP <br> (P) |  |
| $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$ | 11.2 V | NE555D |  |  | NE555P | NE555Y |
| $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ | 11.2 V | SA555D |  |  | SA555P |  |
| $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ | $\begin{aligned} & 10.6 \mathrm{~V} \\ & 11.2 \mathrm{~V} \end{aligned}$ | $\begin{aligned} & \hline \text { SE555D } \\ & \text { SE555CD } \end{aligned}$ | SE555FK SE555CFK | $\begin{aligned} & \hline \text { SE555JG } \\ & \text { SE555CJG } \end{aligned}$ | $\begin{aligned} & \hline \text { SE555P } \\ & \text { SE555CP } \end{aligned}$ |  |

The D package also is available taped and reeled. Add the suffix $R$ to the device type (e.g., NE555DR).

FUNCTION TABLE

| RESET | TRIGGER VOLTAGE $\dagger$ | THRESHOLD VOLTAGE $\dagger$ | OUTPUT | DISCHARGE SWITCH |
| :---: | :---: | :---: | :---: | :---: |
| Low | Irrelevant | Irrelevant | Low | On |
| High | $<1 / 3 V_{\mathrm{DD}}$ | Irrelevant | High | Off |
| High | $>1 / 3 \mathrm{~V}_{\mathrm{DD}}$ | $>2 / 3 \mathrm{~V}_{\mathrm{DD}}$ | Low | On |
| High | $>1 / 3 \mathrm{~V}_{\mathrm{DD}}$ | $<2 / 3 \mathrm{~V}_{\mathrm{DD}}$ | As previously established |  |

$\dagger$ Voltage levels shown are nominal.

## functional block diagram



RESET can override TRIG, which can override THRES.
Pin numbers shown are for the $\mathrm{D}, \mathrm{JG}$, and P packages.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, $\mathrm{V}_{\mathrm{CC}}$ (See Note 1) ........................................................................ 18 . V
Input voltage (CONT, RESET, THRES, and TRIG) ......................................................... $V_{\text {CC }}$
Output current .............................................................................................. 225 mA
Continuous total dissipation ............................................... See Dissipation Rating Table
Package thermal impedance, $\theta_{\text {JA }}$ (see Note 2): D package ........................................ $97^{\circ} \mathrm{C} / \mathrm{W}$
P package .......................................... $85^{\circ} \mathrm{C} / \mathrm{W}$
Case temperature for 60 seconds: FK package .................................................... $260^{\circ} \mathrm{C}$
Lead temperature $1,6 \mathrm{~mm}$ ( $1 / 16 \mathrm{inch}$ ) from case for 10 seconds: D or P package ................... $260^{\circ} \mathrm{C}$
Lead temperature $1,6 \mathrm{~mm}$ ( $1 / 16 \mathrm{inch}$ ) from case for 60 seconds: JG package ..................... $300^{\circ} \mathrm{C}$

NOTES: 1. All voltage values are with respect to network ground terminal.
2. The package thermal impedance is calculated in accordance with JESD 51-7.

DISSIPATION RATING TABLE

| PACKAGE | $\mathrm{T}_{\mathrm{A}} \leq 25^{\circ} \mathrm{C}$ <br> POWER RATING | DERATING FACTOR ABOVE $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | $\mathrm{T}_{\mathrm{A}}=70^{\circ} \mathrm{C}$ <br> POWER RATING | $\mathrm{T}_{\mathrm{A}}=85^{\circ} \mathrm{C}$ <br> POWER RATING | $\mathrm{T}_{\mathrm{A}}=125^{\circ} \mathrm{C}$ <br> POWER RATING |
| :---: | :---: | :---: | :---: | :---: | :---: |
| FK | 1375 mW | 11.0 mW/ ${ }^{\circ} \mathrm{C}$ | 880 mW | 715 mW | 275 mW |
| JG (SE555, SE555C) | 1050 mW | $8.4 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ | 672 mW | 546 mW | 210 mW |
| JG (SA555, NE555C) | 825 mW | 6.6 mW/ ${ }^{\circ} \mathrm{C}$ | 528 mW | 429 mW | N/A |

recommended operating conditions

electrical characteristics, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ to $15 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (unless otherwise noted)


NOTE 3: This parameter influences the maximum value of the timing resistors $R_{A}$ and $R_{B}$ in the circuit of Figure 12. For example, when $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$, the maximum value is $\mathrm{R}=\mathrm{R}_{\mathrm{A}}+\mathrm{R}_{\mathrm{B}} \approx 3.4 \mathrm{M} \Omega$, and for $\mathrm{V}_{\mathrm{CC}}=15 \mathrm{~V}$, the maximum value is $10 \mathrm{M} \Omega$.
operating characteristics, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ and 15 V

| PARAMETER |  | TEST CONDITIONS $\dagger$ | SE555 |  |  | $\begin{aligned} & \text { NE555 } \\ & \text { SA555 } \\ & \text { SE555C } \end{aligned}$ |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| Initial error of timing interval $\ddagger$ | Each timer, monostable§ |  | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | 0.5\% | 1.5\%* |  | 1\% | 3\% |  |
|  | Each timer, astable\ |  |  | 1.5\% |  |  | 2.25\% |  |  |
| Temperature coefficient of timing interval | Each timer, monostable§ | $\mathrm{T}^{\prime}=$ MIN to MAX |  | 30 | 100* |  | 50 |  |  |
|  | Each timer, astablel |  |  | 90 |  |  | 150 |  | ppm/ ${ }^{\text {c }}$ |
| Supply-voltage sensitivity of timing interval | Each timer, monostable§ | $T^{\prime} A=25^{\circ} \mathrm{C}$ |  | 0.05 | $0.2^{*}$ |  | 0.1 | 0.5 |  |
|  | Each timer, astable ${ }^{\text {d }}$ |  |  | 0.15 |  |  | 0.3 |  | \% |
| Output-pulse rise time |  | $\begin{aligned} & \mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}, \\ & \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C} \end{aligned}$ |  | 100 | 200* |  | 100 | 300 | ns |
| Output-pulse fall time |  |  |  | 100 | 200* |  | 100 | 300 | ns |

* On products compliant to MIL-PRF-38535, this parameter is not production tested.
$\dagger$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
$\ddagger$ Timing interval error is defined as the difference between the measured value and the average value of a random sample from each process run.
$\S$ Values specified are for a device in a monostable circuit similar to Figure 9, with the following component values: $R_{A}=2 \mathrm{k} \Omega$ to $100 \mathrm{k} \Omega$, $\mathrm{C}=0.1 \mu \mathrm{~F}$.
TValues specified are for a device in an astable circuit similar to Figure 12, with the following component values: $R_{A}=1 \mathrm{k} \Omega$ to $100 \mathrm{k} \Omega$, $C=0.1 \mu \mathrm{~F}$.
electrical characteristics, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ to $15 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (unless otherwise noted)

| PARAMETER | TEST CONDITIONS |  | NE555Y |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX |  |
| THRES voltage level | $\mathrm{V}_{\mathrm{CC}}=15 \mathrm{~V}$ |  | 8.8 | 10 | 11.2 | V |
|  | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | 2.4 | 3.3 | 4.2 |  |
| THRES current (see Note 4) |  |  |  | 30 | 250 | nA |
| TRIG voltage level | $\mathrm{V}_{\mathrm{CC}}=15 \mathrm{~V}$ |  | 4.5 | 5 | 5.6 | V |
|  | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | 1.1 | 1.67 | 2.2 |  |
| TRIG current | TRIG at 0 V |  |  | 0.5 | 2 | $\mu \mathrm{A}$ |
| RESET voltage level |  |  | 0.3 | 0.7 | 1 | V |
| RESET current | RESET at $\mathrm{V}_{\text {CC }}$ |  |  | 0.1 | 0.4 | mA |
|  | RESET at 0 V |  |  | -0.4 | -1.5 |  |
| DISCH switch off-state current |  |  |  | 20 | 100 | nA |
| CONT voltage (open circuit) | $\mathrm{V}_{C C}=15 \mathrm{~V}$ |  | 9 | 10 | 11 | V |
|  | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | 2.6 | 3.3 | 4 |  |
| Low-level output voltage | $V_{C C}=15 \mathrm{~V}$ | $\mathrm{IOL}=10 \mathrm{~mA}$ |  | 0.1 | 0.25 | V |
|  |  | $\mathrm{I} \mathrm{OL}=50 \mathrm{~mA}$ |  | 0.4 | 0.75 |  |
|  |  | $\mathrm{IOL}=100 \mathrm{~mA}$ |  | 2 | 2.5 |  |
|  |  | $\mathrm{IOL}=200 \mathrm{~mA}$ |  | 2.5 |  |  |
|  | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ | $\mathrm{IOL}=5 \mathrm{~mA}$ |  | 0.1 | 0.35 |  |
|  |  | $\mathrm{IOL}=8 \mathrm{~mA}$ |  | 0.15 | 0.4 |  |
| High-level output voltage | $V_{C C}=15 \mathrm{~V}$ | $\mathrm{IOH}=-100 \mathrm{~mA}$ | 12.75 | 13.3 |  | V |
|  |  | $\mathrm{IOH}=-200 \mathrm{~mA}$ |  | 12.5 |  |  |
|  | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ | $\mathrm{I}^{\mathrm{OH}}=-100 \mathrm{~mA}$ | 2.75 | 3.3 |  |  |
| Supply current | Output low, No load | $\mathrm{V}_{\mathrm{CC}}=15 \mathrm{~V}$ |  | 10 | 15 | mA |
|  |  | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | 3 | 6 |  |
|  | Output high No load | $\mathrm{V}_{C C}=15 \mathrm{~V}$ |  | 9 | 13 |  |
|  | Output high, No load | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | 2 | 5 |  |

NOTES: 4. This parameter influences the maximum value of the timing resistors $R_{A}$ and $R_{B}$ in the circuit of Figure 12. For example, when $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$, the maximum value is $\mathrm{R}=\mathrm{R}_{\mathrm{A}}+\mathrm{R}_{\mathrm{B}} \approx 3.4 \mathrm{M} \Omega$, and for $\mathrm{V}_{\mathrm{CC}}=15 \mathrm{~V}$, the maximum value is $10 \mathrm{M} \Omega$.
operating characteristics, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ and $15 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ (unless otherwise noted)

| PARAMETER |  | TEST CONDITIONS | NE555Y |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | TYP | MAX |  |
| Initial error of timing interval $\dagger$ | Each timer, monostable $\ddagger$ |  |  |  | 1\% | 3\% |  |
|  | Each timer, astable§ |  |  | 25\% |  |  |
| Supply-voltage sensitivity of timing interval | Each timer, monostable $\ddagger$ |  |  | 0.1 | 0.5 | \%/V |
|  | Each timer, astable§ |  |  | 0.3 |  |  |
| Output-pulse rise time |  | $C_{L}=15 \mathrm{pF}$ |  | 100 | 300 | ns |
| Output-pulse fall time |  |  |  | 100 | 300 | ns |

$\dagger$ Timing interval error is defined as the difference between the measured value and the average value of a random sample from each process run.
$\ddagger$ Values specified are for a device in a monostable circuit similar to Figure 9, with the following component values: $R_{A}=2 \mathrm{k} \Omega$ to $100 \mathrm{k} \Omega$, $\mathrm{C}=0.1 \mu \mathrm{~F}$.
$\S$ Values specified are for a device in an astable circuit similar to Figure 12 , with the following component values: $R_{A}=1 \mathrm{k} \Omega$ to $100 \mathrm{k} \Omega$, $\mathrm{C}=0.1 \mu \mathrm{~F}$.

## TYPICAL CHARACTERISTICS $\dagger$



Figure 1

LOW-LEVEL OUTPUT VOLTAGE vs
LOW-LEVEL OUTPUT CURRENT


Figure 3

## LOW-LEVEL OUTPUT VOLTAGE LOW-LEVEL OUTPUT CURRENT



Figure 2

DROP BETWEEN SUPPLY VOLTAGE AND OUTPUT vs
HIGH-LEVEL OUTPUT CURRENT


Figure 4

## TYPICAL CHARACTERISTICS $\dagger$



Figure 5
NORMALIZED OUTPUT PULSE DURATION (MONOSTABLE OPERATION)
vs
FREE-AIR TEMPERATURE


Figure 7

NORMALIZED OUTPUT PULSE DURATION (MONOSTABLE OPERATION)
vs SUPPLY VOLTAGE


Figure 6
PROPAGATION DELAY TIME
vs
LOWEST VOLTAGE LEVEL OF TRIGGER PULSE


Figure 8
$\dagger$ Data for temperatures below $0^{\circ} \mathrm{C}$ and above $70^{\circ} \mathrm{C}$ are applicable for SE555-series circuits only.

## APPLICATION INFORMATION

## monostable operation

For monostable operation, any of these timers can be connected as shown in Figure 9. If the output is low, application of a negative-going pulse to TRIG sets the flip-flop ( $\overline{\mathrm{Q}}$ goes low), drives the output high, and turns off Q1. Capacitor C then is charged through $\mathrm{R}_{\mathrm{A}}$ until the voltage across the capacitor reaches the threshold voltage of THRES input. If TRIG has returned to a high level, the output of the threshold comparator will reset the flip-flop ( $\overline{\mathrm{Q}}$ goes high), drive the output low, and discharge C through Q1.


Pin numbers shown are for the $D, J G$, and $P$ packages.
Figure 9. Circuit for Monostable Operation
Monostable operation is initiated when TRIG voltage falls below the trigger threshold. Once initiated, the sequence ends only if TRIG is high at the end of the timing interval. Because of the threshold level and saturation voltage of Q1, the output pulse duration is approximately $t_{w}=1.1 R_{A} C$. Figure 11 is a plot of the time constant for various values of $R_{A}$ and $C$. The threshold levels and charge rates both are directly proportional to the supply voltage, $\mathrm{V}_{\mathrm{Cc}}$. The timing interval is, therefore, independent of the supply voltage, so long as the supply voltage is constant during the time interval.

Applying a negative-going trigger pulse simultaneously to RESET and TRIG during the timing interval discharges C and re-initiates the cycle, commencing on the positive edge of the reset pulse. The output is held low as long as the reset pulse is low. To prevent false triggering, when RESET is not used, it should be connected to $\mathrm{V}_{\mathrm{CC}}$.


Time- $0.1 \mathrm{~ms} / \mathrm{div}$
Figure 10. Typical Monostable Waveforms


Figure 11. Output Pulse Duration vs Capacitance

## APPLICATION INFORMATION

## astable operation

As shown in Figure 12, adding a second resistor, $\mathrm{R}_{\mathrm{B}}$, to the circuit of Figure 9 and connecting the trigger input to the threshold input causes the timer to self-trigger and run as a multivibrator. The capacitor C charges through $R_{A}$ and $R_{B}$ and then discharges through $R_{B}$ only. Therefore, the duty cycle is controlled by the values of $R_{A}$ and $\mathrm{R}_{\mathrm{B}}$.
This astable connection results in capacitor C charging and discharging between the threshold-voltage level $\left(\approx 0.67 \bullet \mathrm{~V}_{\mathrm{CC}}\right)$ and the trigger-voltage level $\left(\approx 0.33 \bullet \mathrm{~V}_{\mathrm{CC}}\right)$. As in the monostable circuit, charge and discharge times (and, therefore, the frequency and duty cycle) are independent of the supply voltage.


Pin numbers shown are for the $\mathrm{D}, \mathrm{JG}$, and $P$ packages.
NOTE A: Decoupling CONT voltage to ground with a capacitor can improve operation. This should be evaluated for individual applications.
Figure 12. Circuit for Astable Operation


Figure 13. Typical Astable Waveforms

## APPLICATION INFORMATION

Figure 13 shows typical waveforms generated during astable operation. The output high-level duration $t_{H}$ and low-level duration $t_{L}$ can be calculated as follows:

$$
\begin{aligned}
& t_{H}=0.693\left(R_{A}+R_{B}\right) C \\
& t_{L}=0.693\left(R_{B}\right) C
\end{aligned}
$$

Other useful relationships are shown below.

$$
\begin{aligned}
& \text { period }=t_{H}+t_{L}=0.693\left(R_{A}+2 R_{B}\right) C \\
& \text { frequency } \approx \frac{1.44}{\left(R_{A}+2 R_{B}\right) C}
\end{aligned}
$$

Output driver duty cycle $=\frac{t_{L}}{t_{H}+t_{L}}=\frac{R_{B}}{R_{A}+2 R_{B}}$
Output waveform duty cycle

$$
=\frac{t_{H}}{t_{H}+t_{L}}=1-\frac{R_{B}}{R_{A}+2 R_{B}}
$$

Low-to-high ratio $=\frac{t_{L}}{t_{H}}=\frac{R_{B}}{R_{A}+R_{B}}$


Figure 14. Free-Running Frequency

## missing-pulse detector

The circuit shown in Figure 15 can be used to detect a missing pulse or abnormally long spacing between consecutive pulses in a train of pulses. The timing interval of the monostable circuit is retriggered continuously by the input pulse train as long as the pulse spacing is less than the timing interval. A longer pulse spacing, missing pulse, or terminated pulse train permits the timing interval to be completed, thereby generating an output pulse as shown in Figure 16.


Pin numbers shown are shown for the $D, J G$, and $P$ packages.
Figure 15. Circuit for Missing-Pulse Detector


Figure 16. Circuit for Missing-Pulse Detector

## APPLICATION INFORMATION

## frequency divider

By adjusting the length of the timing cycle, the basic circuit of Figure 9 can be made to operate as a frequency divider. Figure 17 shows a divide-by-three circuit that makes use of the fact that retriggering cannot occur during the timing cycle.


Figure 17. Divide-By-Three Circuit Waveforms

## pulse-width modulation

The operation of the timer can be modified by modulating the internal threshold and trigger voltages, which is accomplished by applying an external voltage (or current) to CONT. Figure 18 shows a circuit for pulse-width modulation. A continuous input pulse train triggers the monostable circuit, and a control signal modulates the threshold voltage. Figure 19 shows the resulting output pulse-width modulation. While a sine-wave modulation signal is illustrated, any wave shape could be used.

## APPLICATION INFORMATION



Pin numbers shown are for the $\mathrm{D}, \mathrm{JG}$, and P packages.
NOTE A: The modulating signal can be direct or capacitively coupled to CONT. For direct coupling, the effects of modulation source voltage and impedance on the bias of the timer should be considered.

Figure 18. Circuit for Pulse-Width Modulation


Figure 19. Pulse-Width Modulation Waveforms

## pulse-position modulation

As shown in Figure 20, any of these timers can be used as a pulse-position modulator. This application modulates the threshold voltage, and, thereby, the time delay, of a free-running oscillator. Figure 21 shows a triangular-wave modulation signal for such a circuit; however, any wave shape could be used.


Pin numbers shown are for the $\mathrm{D}, \mathrm{JG}$, and $P$ packages.
NOTE A: The modulating signal can be direct or capacitively coupled to CONT. For direct coupling, the effects of modulation source voltage and impedance on the bias of the timer should be considered.

Figure 20. Circuit for Pulse-Position Modulation


Figure 21. Pulse-Position-Modulation Waveforms

## APPLICATION INFORMATION

## sequential timer



S closes momentarily at $t=0$.
Pin numbers shown are for the D, JG, and P packages.
Figure 22. Sequential Timer Circuit
Many applications, such as computers, require signals for initializing conditions during start-up. Other applications, such as test equipment, require activation of test signals in sequence. These timing circuits can be connected to provide such sequential control. The timers can be used in various combinations of astable or monostable circuit connections, with or without modulation, for extremely flexible waveform control. Figure 22 shows a sequencer circuit with possible applications in many systems, and Figure 23 shows the output waveforms.


Figure 23. Sequential Timer Waveforms

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